

<b>Notice of References Cited</b>	Application/Control No. 10/820,494		Applicant(s)/Patent Under Reexamination DESAI ET AL	
	Examiner A. Sefer		Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0218426	10-2005	Kobayashi et al.	257/177
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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